

N-Channel 30 V (D-S) 175 °C MOSFET

DESCRIPTION

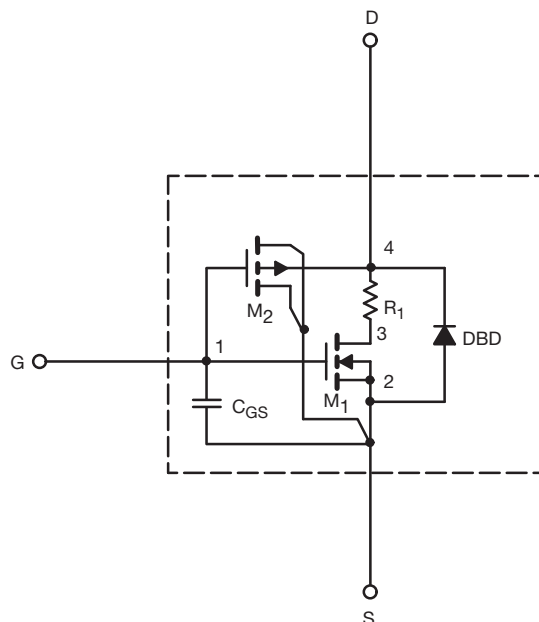
The attached SPICE model describes the typical electrical characteristics of the n-channel vertical DMOS. The subcircuit model is extracted and optimized over the - 55 °C to 125 °C temperature ranges under the pulsed 0 V to 10 V gate drive. The saturated output impedance is best fit at the gate bias near the threshold voltage.

A novel gate-to-drain feedback capacitance network is used to model the gate charge characteristics while avoiding convergence difficulties of the switched C_{gd} model. All model parameter values are optimized to provide a best fit to the measured electrical data and are not intended as an exact physical interpretation of the device.

CHARACTERISTICS

- N-Channel Vertical DMOS
- Macro Model (Subcircuit Model)
- Level 3 MOS
- Apply for both Linear and Switching Application
- Accurate over the - 55 °C to + 125 °C Temperature Range
- Model the Gate Charge

SUBCIRCUIT MODEL SCHEMATIC



Note

- This document is intended as a SPICE modeling guideline and does not constitute a commercial product datasheet. Designers should refer to the appropriate datasheet of the same number for guaranteed specification limits.



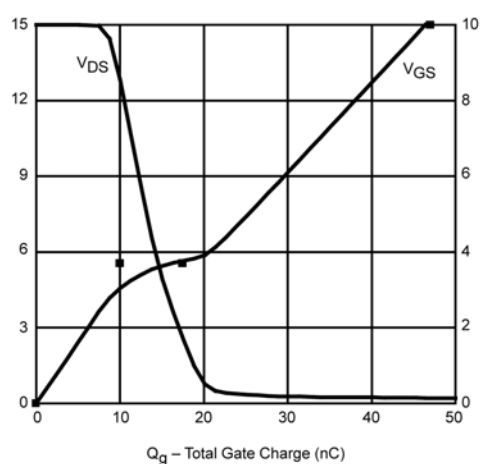
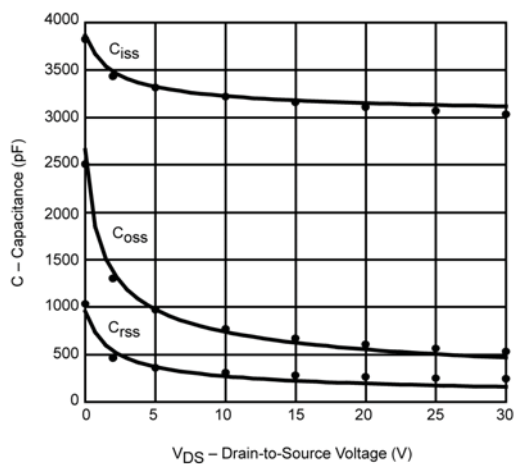
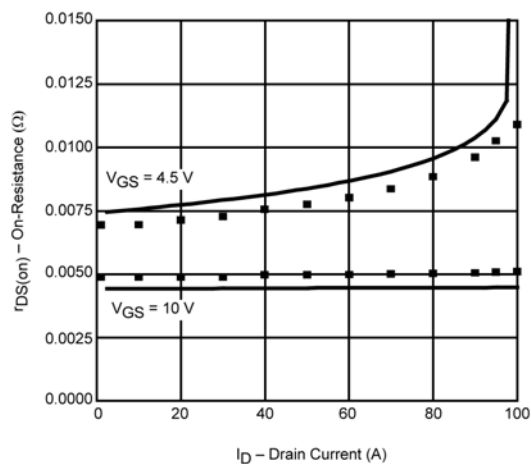
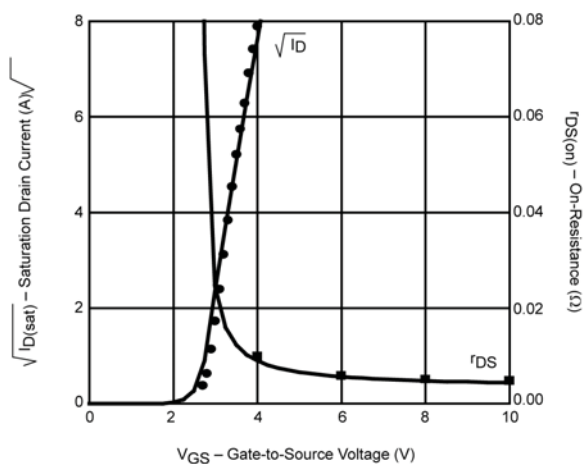
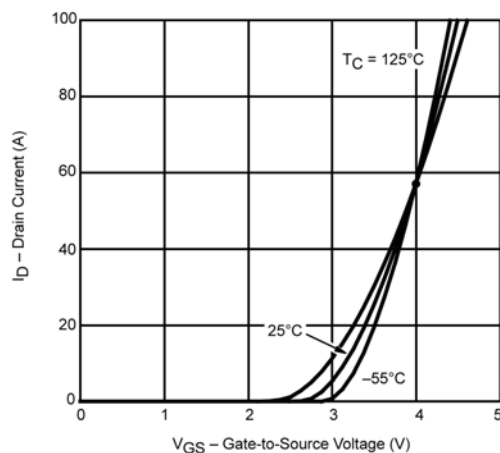
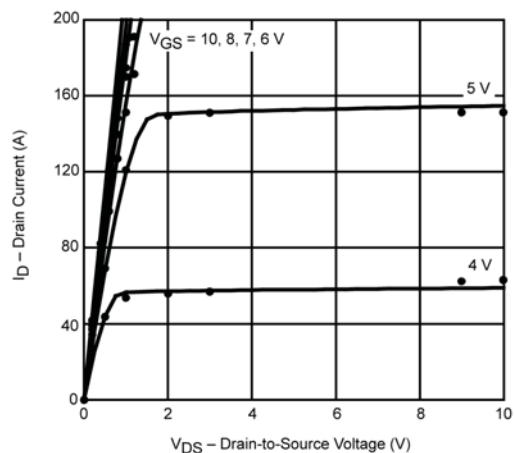
| SPECIFICATIONS ($T_J = 25\text{ }^{\circ}\text{C}$, unless otherwise noted) | | | | | |
|---|--------------|---|----------------|---------------|----------|
| PARAMETER | SYMBOL | TEST CONDITIONS | SIMULATED DATA | MEASURED DATA | UNIT |
| Static | | | | | |
| Gate Threshold Voltage | $V_{GS(th)}$ | $V_{DS} = V_{GS}$, $I_D = 250\text{ }\mu\text{A}$ | 1.8 | - | V |
| On-State Drain Current ^a | $I_{D(on)}$ | $V_{DS} = 5\text{ V}$, $V_{GS} = 10\text{ V}$ | 923 | - | A |
| Drain-Source On-State Resistance ^a | $R_{DS(on)}$ | $V_{GS} = 10\text{ V}$, $I_D = 20\text{ A}$ | 0.0044 | 0.0053 | Ω |
| | | $V_{GS} = 10\text{ V}$, $I_D = 20\text{ A}$, $T_J = 125\text{ }^{\circ}\text{C}$ | 0.0080 | - | |
| | | $V_{GS} = 4.5\text{ V}$, $I_D = 20\text{ A}$ | 0.0077 | 0.0078 | |
| Diode Forward Voltage | V_{SD} | $I_S = 100\text{ A}$, $V_{GS} = 0\text{ V}$ | 0.89 | 1.2 | V |
| Dynamic^b | | | | | |
| Input Capacitance | C_{iss} | $V_{DS} = 25\text{ V}$, $V_{GS} = 0\text{ V}$, $f = 1\text{ MHz}$ | 3155 | 3100 | pF |
| Output Capacitance | C_{oss} | | 509 | 565 | |
| Reverse Transfer Capacitance | C_{rss} | | 177 | 255 | |
| Total Gate Charge | Q_g | $V_{DS} = 15\text{ V}$, $V_{GS} = 10\text{ V}$, $I_D = 50\text{ A}$ | 47 | 48 | nC |
| Gate-Source Charge | Q_{gs} | | 10 | 10 | |
| Gate-Drain Charge | Q_{gd} | | 7.5 | 7.5 | |
| Turn-On Delay Time | $t_{d(on)}$ | $V_{DD} = 15\text{ V}$, $R_L = 0.3\text{ }\Omega$ $I_D = 50\text{ A}$, $V_{GEN} = 10\text{ V}$, $R_g = 2.5\text{ }\Omega$ | 10 | 12 | ns |
| Rise Time | t_r | | 14 | 12 | |
| Turn-Off Delay Time | $t_{d(off)}$ | | 26 | 30 | |
| Fall Time | t_f | | 33 | 10 | |
| Source-Drain Reverse Recovery Time | t_{rr} | $I_F = 50\text{ A}$, $dI/dt = 100\text{ A}/\mu\text{s}$ | 31 | 35 | |

Notes

- a. Pulse test; pulse width $\leq 300\text{ }\mu\text{s}$, duty cycle $\leq 2\%$.
b. Guaranteed by design, not subject to production testing.



COMPARISON OF MODEL WITH MEASURED DATA ($T_J = 25^\circ\text{C}$, unless otherwise noted)



Note

- Dots and squares represent measured data.